## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | RHEE ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,031,512	02-2000	Kadota et al.	345/88
	В	US-5,754,261	05-1998	Lyu, Ki Hyun	349/44
	С	US-RE33,882	04-1992	Morozumi, Shinji	345/88
Î	D	US-6,787,275	09-2004	Kawase, Tomomi	430/7
	Е	US-5,587,819	12-1996	Sunohara et al.	349/106
	F	US-2002/0074549	06-2002	Park et al.	257/59
	G	US-6,798,471	09-2004	Yamada, Tsutomu	349/106
	Н	US-2002/0145695	10-2002	Kim et al.	349/141
	ı	US-6,785,068	08-2004	Takizawa et al.	359/885
	J	US-			
	к	US-			
'	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*	į	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ö					
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	S			:		
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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	>							
	8							
	x							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.